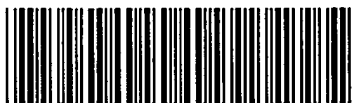


Search Notes

Application/Control No.

10/656,818

Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under
Reexamination

BOTHWELL ET AL.

Art Unit

3634

SEARCHED

Class	Subclass	Date	Examiner
	<i>update</i>	<i>1.11.06</i>	<i>AL</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
<i>182</i>	<i>222</i>	<i>1.11.06</i>	<i>AL</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR